

Specification for Approval

Date: 2012/11/16

Customer: 天河

TAI-TECH P/N:	TMPC0512HP	2-1R0MG-D
CUSTOMER P/N:		
DESCRIPTION:		
QUANTITY:	50	pcs

REMARK:		
Cu	stomer Approval Feedba	ack

□ 西北臺慶科技股份有限公司

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BTMC55101R0M05 TA734003

SMD Power Choke Coil

TMPC0512HP-1R0MG-D

		ECN HISTOR	RY LIS	Γ	
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	12/11/16	新 發 行	許智良	張榮泉	徐允珮
備					
註					

TAI-TECH

SMD Power Choke Coil

TMPC0512HP-1R0MG-D

1. Features

- 1. Carbonyl powder inductor.
- 2. Compact design.
- 3. High current , low DCR , high efficiency.
- 4. Very low acoustic noise and very low leakage flux noise.
- 5. High reliability.
- 6. 100% Lead(Pb) & Halogen-Free and RoHS compliant.



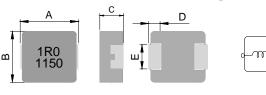


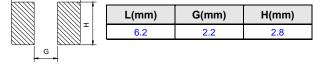
2. Applications

Note PC power system , incl. IMVP-6 DC/DC converter.



Recommend PC Board Pattern





Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)
TMPC0512HP	5.7±0.3	5.2±0.2	1.0±0.2	1.1±0.3	2.5±0.3

4. Part Numbering



A: Series

B: Dimension BxC

H: Carbonyl powder, P: PAD broaden C: Type

1R0=1.0uH D: Inductance E: Inductance Tolerance M=±20%

F: D/C 印字:黑色, 1R0 及 D/C 1150 (D/C 前二碼是年份,後二碼是週期,依實際生產週期而定)

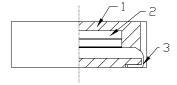
5. Specification

Part Number	Inductance	l rms	I sat	DCR	DCR
	L0 (uH) ±20% @ 0 A	(A) typ.	(A) typ.	(mΩ) typ. @25℃	(mΩ) max. @25℃
TMPC0512HP-1R0MG-D	1.00	5.0	6.0	26	30

Note:

- 1. Test frequency: L: 100KHz/1.0V
- 2. All test data referenced to 25°C ambient.
- $3. \ \ \mathsf{Testing\ Instrument: L/Q: HP4284A, CH11025, CH3302, CH1320\ CH1320\ SLCR\ METER\ /\ Rdc: CH16502, Agilent 33420A\ MICRO\ OHMMETER.}$
- 5. Saturation Current (Isat) will cause L0 $\,$ to drop $\,\leq\,$ 20% typical. (keep quickly).
- 6. The part temperature (ambient + temp rise) should not exceed 125°C under worst case operating conditions. Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.
- 7. Special inquiries besides the above common used types can be met on your requirement.

6. Material List



NO	Items	Materials	
1	Core	Carbonyl powder or equ.	
2	Wire	Polyester Wire or equivalent.	
3	Solder Plating	100% Pb free solder	

7. Reliability and Test Condition

Item	Performance	Test Condition
Operating temperature	-40~+125℃	
Storage temperature and Humidity range	-40-+125℃ (For products in unopened tape package, less than 40℃) 50-60%RH (Product without taping)	
Electrical Performance Tes	st	
Inductance	Refer to standard electrical characteristics list.	HP4284A,CH11025,CH3302,CH1320,CH1320S LCR Meter.
DCR	Note: to statistical discussion states and	CH16502,Agilent33420A Micro-Ohm Meter.
Saturation Current (Isat)	△L≦20% typical.	Saturation DC Current (Isat) will cause L0 to drop \triangle L(%)(keep quickly).
Heat Rated Current (Irms)	Approximately △T≤40°C	Heat Rated Current (Irms) will cause the coil temperature rise $\Delta T(\mathbb{C})$ without core loss. 1.Applied the allowed DC current(keep 1 min.). 2.Temperature measured by digital surface thermometer
Reliability Test		
High Temperature Exposure Test		Temperature:125±2°C. Duration:1000±12hrs. Measured at room temperature after placing for 2 to 3hrs. (MIL-PRF-27)
Low Temperature Life Test		Temperature:-40±2°C. Duration:500±12hrs. Measured at room temperature after placing for 2 to 3hrs.
Biased Humidity Test		Humidity:85±3%RH. Temperature:85±2°C. Duration:1000±12hrs. Measured at room temperature after placing for 2 to 3hrs (AEC-Q200-REV C)
Thermal shock test	Electric specifications should be satisfied	Condition for 1 cycle $\label{eq:condition} \begin{tabular}{ll} Step1:-40+0/-2^{\circ}\mathbb{C} & 15\pm 1 \mbox{ min.} \\ Step2:Room temperature within $\leq 0.2 \mbox{ min.} \\ Step3:+125+2/-0^{\circ}\mathbb{C} & 15\pm 1 \mbox{min.} \\ Number of cycles:300 \\ Measured at room temperature after placing for 2 to 3 hrs. \\ (AEC-Q200-REV C) \end{tabular}$
Vibration test		Frequency: 10-2000-10Hz for 20 min. Amplitude: Parts mounted within 2" from any secure point. Directions and times: X, Y, Z directions for 20 min. This cycle shall be performed 12 times in each of three mutually perpendicular directions (Total 12hours). (MIL-STD-202 Method 204 D Test condition B)
Reflow test		Pre-heat : 150±5℃ Duration : 5 minutes Temperature : 260±5℃ · 20~40 seconds (IPC/JEDEC J-STD-020C)
Solder test	Terminals should be covered by over 95% solder on visual inspection	After dip into flux · dip into solder 235±5°C · 4±1 seconds Flux · solder for lead free (ANSI /J-STD-002C Method B)

8. Soldering and Mounting

(1) Soldering

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. TAI-TECH terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

(2) Solder re-flow:

Recommended temperature profiles for re-flow soldering in Figure 1.

(3) Soldering Iron:

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm

- 355℃ tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5sec.

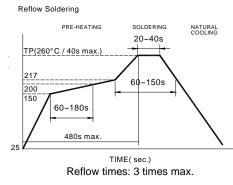
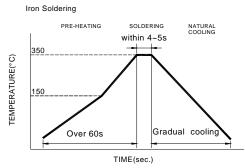


Fig.1

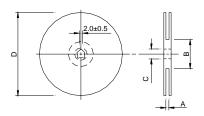


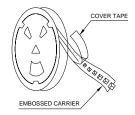
Iron Soldering times: 1 times max.

Fig.2

9. Packaging Information

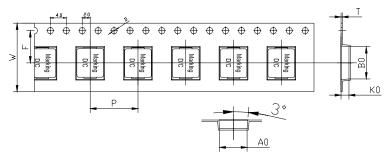
(1) Reel Dimension





Туре	A(mm)	B(mm)	C(mm)	D(mm)
13"x12mm	12.0±0.5	100±2	13.5±0.5	330

(2) Tape Dimension

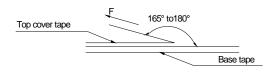


Series	Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	W(mm)	F(mm)	t(mm)	D(mm)
TMPC	0512	6.2±0.1	5.5±0.1	1.5±0.1	8.0±0.1	12.0±0.3	5.5±0.1	0.35±0.05	1.5±0.1

(3) Packaging Quantity

ТМРС	0512
Chip / Reel	4000
Inner box	8000
Carton	32000

(4) Tearing Off Force



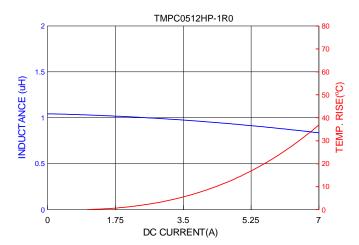
The force for tearing off cover tape is 10 to 130 grams in the arrow direction under the following conditions(referenced ANSI/EIA-481-C-2003 of 4.11 stadnard).

Room Temp.	Room Humidity	Room atm	Tearing Speed
(℃)	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

Application Notice

- Storage Conditions
 - To maintain the solderability of terminal electrodes:
 - 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
 - 2. Temperature and humidity conditions: Less than 40°C and 60% RH.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

10. Typical Performance Curves





测試報告

Test Report

號碼(No.) : CE/2012/31072 日期(Date) : 2012/03/09 頁數(Page) : 1 of 7

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(廣東省東莞市黄江鎮黄牛埔福祥街2號 / NO. 2, FUXIANG STREET, HUANGNIUPU, HUANGJIANG TOWN, DONGGUAN, GUANGDONG) 《江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

以下測試樣品係由客户送樣, 且由客户聲稱並經客户確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

樣品名稱(Sample Description)

: TMPB, TMPC, SLPI, SEPI, SMPI, SMPI-P3, EPI(ePI), TIB, LRPI, HCM, VMPI,

MLPI SERIES

樣品型號(Style/Item No.)

TMPB, TMPC, SLPI, SEPI, SMP1, SMP1-P3, EPI(ePI), TIB, LRPI, HCM, VMPI,

MLPI SERIES

收件日期(Sample Receiving Date)

2012/03/03

測試期間(Testing Period)

2012/03/03 TO 2012/03/09

測試結果(Test Results)

請見下一頁 (Please refer to next pages).

Chenyu Kung / Signed for and on selfalfield SGS TAIWAN LTD. Chemical Laboratory - Taipei

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測試報告 Test Report

號碼(No.): CE/2012/31072 日期(Date): 2012/03/09 頁數(Page): 2 of 7

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* Œ/ 2012/ 31072*

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測試結果(Test Results)

測試部位(PART NAME) No.1 :

整體混測 (11款) (MIXED ALL PARTS (11 KINDS))

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鎬 / Cadmium (Cd)	mg/kg	參考IEC 62321: 2008方法, 以感 應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	参考IEC 62321: 2008方法,以感 應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	参考IEC 62321: 2008方法,以感 應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and perfouned by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	冬考IEC 62321: 2008方法,以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
鹵素 / Halogen			5.0	
鹵素(氣)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)			0.0	n.d.
鹵素(氯)/ Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582:2007, 以離子層 析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(溴)/ Halogen-Browine (Br) (CAS No.: 10097-32-2)			50	n.d.
鹵素(碘)/ Halogen-Iodine(I) (CAS No.: 14362-44-8)			50	n.d.

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號碼(No.): CE/2012/31072 日期(Date): 2012/03/09 頁數(Page): 3 of 7

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs		ià	-	n.d.
一溴聯苯 / Monobromobiphenyl			5	n.d.
二溴聯苯 / Dibromobiphenyl			55	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl		est	5	n.d.
六溴聯苯 / Hexabromobiphenyl		*	5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
入溴聯苯 / Octabromobipheny!		Programme	5	n.d.
九溴聯苯 / Nonabromobiphenyl		參考IEC 62321: 2008方法, 以氣	5	n.d.
十溴聯苯 / Decabromobiphenyl		相層析儀/質譜儀檢測. / With	5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	reference to IEC 62321: 2008		n.d.
一溴聯苯醚 / Monobromodiphenyl ether		and performed by GC/MS.	5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether		Ten de contractor	5	n.d.
入溴聯苯醚 / Octabromodipheny! ether		La management of the Control of the	5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether			5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.

備註(Note):

- 1. mg/kg = ppm : 0.1wt% = 1000ppm
- 🏄 💆 2. n.d. = Not Detected (未檢出)
 - 3, MDL = Method Detection Limit (方法偵測極限値)
 - 4. "-" = Not Regulated (無規格値)
 - 5. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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测试报告

Test Report

號碼(No.): CE/2012/31072 日朝(Date): 2012/03/09 頁數(Page): 4 of 7

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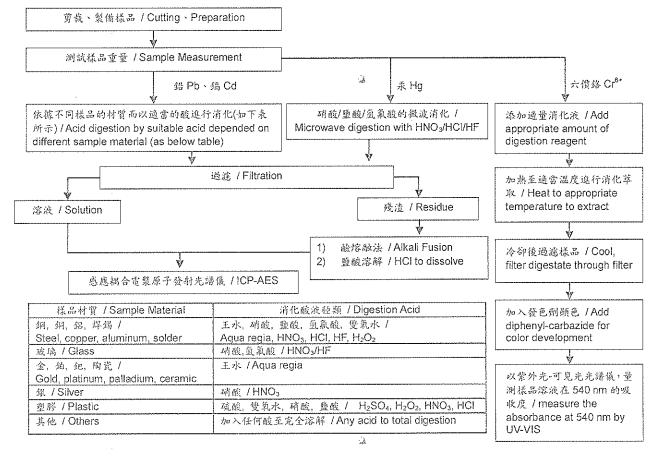
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- 根據以下的流程圖之條件,樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 測試人員: 楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 測試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



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測試報告

Test Report

號碼(No.): CE/2012/31072 日期(Date): 2012/03/09 頁數(Page): 5 of 7

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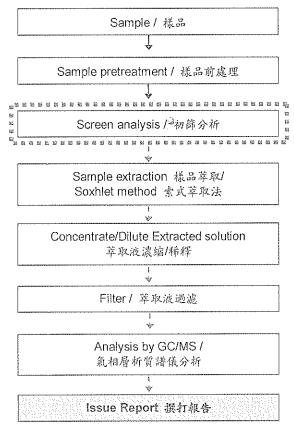
多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong

測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang

初次测试程序 / First testing process ———>

確認程序 / Confirmation process -- · -- -- -- --



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测试報告 Test Report

號碼(No.) : CE/2012/31072 日期(Date) : 2012/03/09 頁數(Page) : 6 of 7

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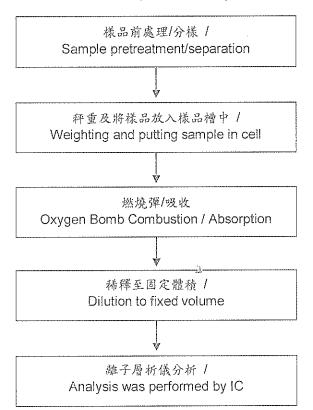
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鹵素分析流程圖 / Analytical flow chart of halogen content

测試人員: 陳恩臻 / Name of the person who made measurement: Rita Chen

測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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Test Report

號碼(No.) : CE/2012/31072 日期(Date) : 2012/03/09 頁數(Page) : 7 of 7

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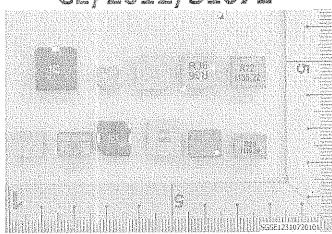
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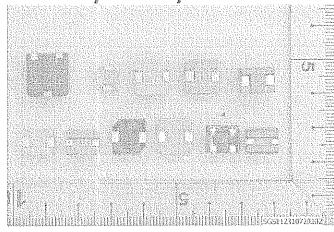
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* 照片中如有箭頭標示,則表示為實際檢測之樣品/部位. *

(The tested sample / part is marked by an arrow if it's shown on the photo.)



CE/2012/31072



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